XN05553G

Silicon NPN epitaxial planar type

For low-frequency amplification

■ Features

- Two elements incorporated into one package
- Reduction of the mounting area and assembly cost by one half

■ Basic Part Number

• 2SD1149 × 2

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V _{CBO}	100	V	
Collector-emitter voltage (Base open)	V _{CEO}	100	V	
Emitter-base voltage (Collector open)	V_{EBO}	15	v	
Collector current	I _C	20	mA	
Peak collector current	I _{CP}	50	mA	
Total power dissipation	P _T	300	mW	
Junction temperature	T_{j}	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

■ Package

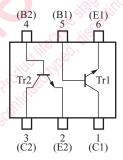
Code Mini6-G3

• Pin Name

1: Collector (Tr1) 4: Base (Tr2) 2: Emitter (Tr2) 5: Base (Tr1) 3: Collector (Tr2) 6: Emitter (Tr1)

■ Marking Symbol: 4U

■ Internal Connection

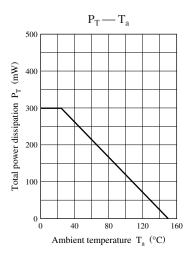


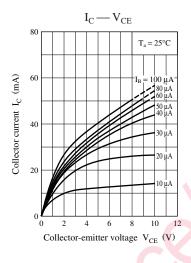
■ Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

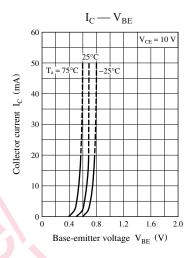
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_C = 10 \mu\text{A}, I_E = 0$	100			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = 1 \text{ mA}, I_B = 0$	100			V
Emitter-base voltage (Collector open)	V_{EBO}	$I_E = 10 \mu A, I_C = 0$	15			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 60 \text{ V}, I_{E} = 0$			0.1	μΑ
Collector-emitter cutoff current (Base open)	I_{CEO}	$V_{CE} = 60 \text{ V}, I_{B} = 0$			1.0	μΑ
Forward current transfer ratio	h_{FE}	$V_{CE} = 10 \text{ V}, I_{C} = 2 \text{ mA}$	400		2000	_
h _{FE} ratio *	h _{FE(Small}	$V_{CE} = 4 \text{ V}, I_{C} = 5 \text{ mA}$	0.50	0.99		_
8.	/Large)					
Collector-emitter saturation voltage	V _{CE(sat)}	$I_C = 10 \text{ mA}, I_B = 1 \text{ mA}$		0.05	0.20	V
Noise voltage	NV	$V_{CE} = 10 \text{ V}, I_{C} = 1 \text{ mA}, G_{V} = 80 \text{ dB}$		80		mV
		$R_g = 100 \text{ k}\Omega$, Function = FLAT				
Transition frequency	f_T	$V_{CB} = 10 \text{ V}, I_{E} = -2 \text{ mA}, f = 200 \text{ MHz}$		150		MHz

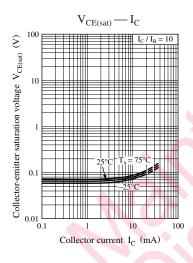
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

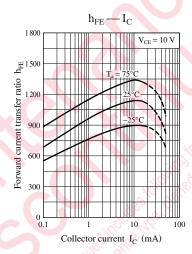
2. *: Ratio between 2 elements

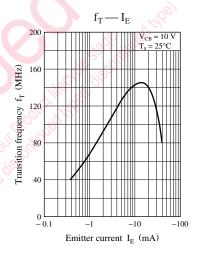


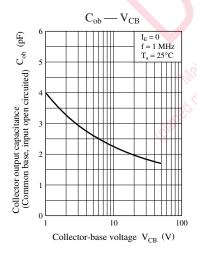


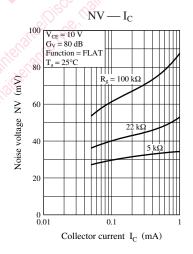


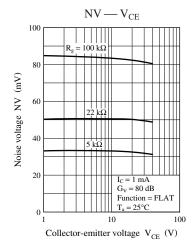






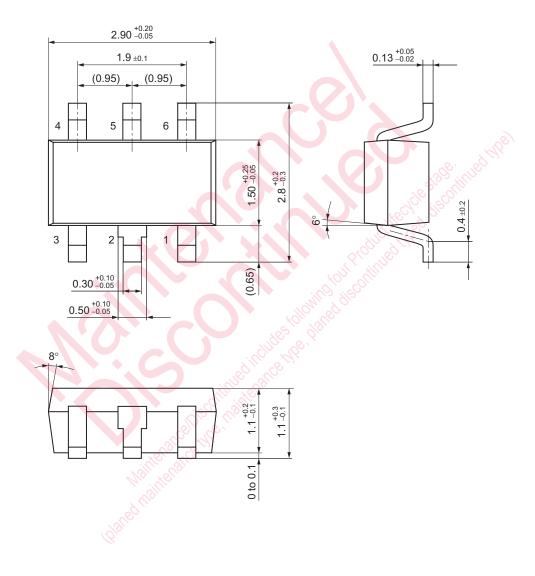






2 SJJ00497AED

Mini6-G3 Unit: mm



SJJ00497AED 3

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